











DRV5055-Q1 SBAS639C - OCTOBER 2017-REVISED JULY 2018

DRV5055-Q1 Automotive Ratiometric Linear Hall Effect Sensor

Features

- Ratiometric Linear Hall Effect Magnetic Sensor
- Operates From 3.3-V and 5-V Power Supplies
- Analog Output With V_{CC} / 2 Quiescent Offset
- Magnetic Sensitivity Options (At $V_{CC} = 5 \text{ V}$):
 - A1: 100 mV/mT, ±21-mT Range
 - A2: 50 mV/mT, ±42-mT Range
 - A3: 25 mV/mT, ±85-mT Range
 - A4: 12.5 mV/mT, ±169-mT Range
 - A5: –100 mV/mT, ±21-mT Range
- Fast 20-kHz Sensing Bandwidth
- Low-Noise Output With ±1-mA Drive
- Compensation For Magnet Temperature Drift
- AEC-Q100 Qualified for Automotive Applications:
 - Temperature Grade 0: –40°C to 150°C
- Standard Industry Packages:
 - Surface-Mount SOT-23
 - Through-Hole TO-92

Applications

- **Automotive Position Sensing**
- Brake, Acceleration, Clutch Pedals
- Torque Sensors, Gear Shifters
- Throttle Position, Height Leveling
- Powertrain and Transmission Components
- Absolute Angle Encoding
- **Current Sensing**

3 Description

The DRV5055-Q1 is a linear Hall effect sensor that responds proportionally to magnetic flux density. The device can be used for accurate position sensing in a wide range of applications.

The device operates from 3.3-V or 5-V power supplies. When no magnetic field is present, the analog output drives half of V_{CC}. The output changes linearly with the applied magnetic flux density, and five sensitivity options enable maximal output voltage swing based on the required sensing range. North and south magnetic poles produce unique voltages.

Magnetic flux perpendicular to the top of the package is sensed, and the two package options provide different sensing directions.

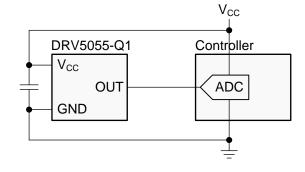
The device uses a ratiometric architecture that can eliminate error from V_{CC} tolerance when the external analog-to-digital converter (ADC) uses the same V_{CC} for its reference. Additionally, the device features magnet temperature compensation to counteract how magnets drift for linear performance across a wide -40°C to +150°C temperature range.

Device Information⁽¹⁾

	PART NUMBER	PACKAGE	BODY SIZE (NOM)	
	DRV5055-Q1	SOT-23 (3)	2.92 mm × 1.30 mm	
		TO-92 (3)	4.00 mm × 3.15 mm	

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Typical Schematic



Magnetic Response (A1, A2, A3, A4 Versions)

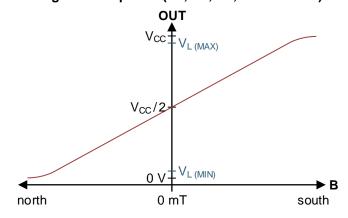




Table of Contents

1	Features 1	7.4 Device Functional Modes13
2	Applications 1	8 Application and Implementation
3	Description 1	8.1 Application Information
4	Revision History	8.2 Typical Application
5	Pin Configuration and Functions3	8.3 Do's and Don'ts
6	Specifications	9 Power Supply Recommendations 18
•	6.1 Absolute Maximum Ratings	10 Layout 18
	6.2 ESD Ratings 4	10.1 Layout Guidelines 18
	6.3 Recommended Operating Conditions 4	10.2 Layout Examples18
	6.4 Thermal Information	11 Device and Documentation Support 19
	6.5 Electrical Characteristics4	11.1 Documentation Support
	6.6 Magnetic Characteristics 5	11.2 Receiving Notification of Documentation Updates 19
	6.7 Typical Characteristics 6	11.3 Community Resources
7	Detailed Description9	11.4 Trademarks 19
	7.1 Overview 9	11.5 Electrostatic Discharge Caution
	7.2 Functional Block Diagram9	11.6 Glossary19
	7.3 Feature Description9	12 Mechanical, Packaging, and Orderable Information19

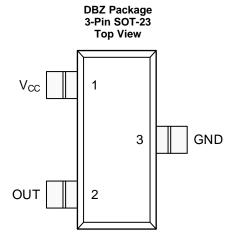
4 Revision History

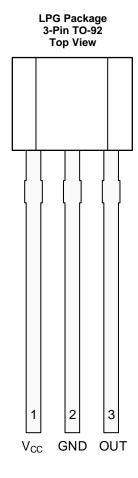
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Cł	changes from Revision B (January 2018) to Revision C	Page
•	Released to production	1



5 Pin Configuration and Functions





Pin Functions

PIN		1/0	DESCRIPTION		
NAME	SOT-23	TO-92	I/O	DESCRIPTION	
V _{CC}	1	1	_	Power supply. TI recommends connecting this pin to a ceramic capacitor to ground with a value of at least 0.01 μF .	
OUT	2	3	0	Analog output	
GND	3	2	_	Ground reference	

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

	<u> </u>				
			MIN	MAX	UNIT
Power supply voltage	V _{CC}		-0.3	7	V
Output voltage	OUT		-0.3	V _{CC} + 0.3	V
Magnetic flux density, B _{MAX}	Unl	imited	Т		
Operating junction temperature, T _J			-40	170	°C
Storage temperature, T _{stg}			-65	150	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



6.2 ESD Ratings

			VALUE	UNIT
V	Human bo	Human body model (HBM), per AEC Q100-002 ⁽¹⁾	±2500	\/
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per AEC Q100-011	±750	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
\ <u>\</u>	Power supply voltage (1)	3	3.63	\/
V _{CC}	Power-supply voltage ⁽¹⁾	4.5	5.5	V
Io	Output continuous current	-1	1	mA
T _A	Operating ambient temperature ⁽²⁾	-40	150	°C

There are two isolated operating V_{CC} ranges. For more information see the Operating V_{CC} Ranges section.
 Power dissipation and thermal limits must be observed.

6.4 Thermal Information

		DRV50		
	THERMAL METRIC ⁽¹⁾	SOT-23 (DBZ)	TO-92 (LPG)	UNIT
		3 PINS	3 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	170	121	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	66	67	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	49	97	°C/W
Y_{JT}	Junction-to-top characterization parameter	1.7	7.6	°C/W
Y_{JB}	Junction-to-board characterization parameter	48	97	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.5 Electrical Characteristics

for V_{CC} = 3 V to 3.63 V and 4.5 V to 5.5 V, over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDI	TIONS ⁽¹⁾	MIN	TYP	MAX	UNIT	
I _{CC}	Operating supply current				6	10	mA	
t _{ON}	Power-on time (see Figure 18)	B = 0 mT, no load on	OUT		175	330	μs	
f _{BW}	Sensing bandwidth				20		kHz	
t _d	Propagation delay time	From change in B to o	change in OUT		10		μs	
D	land referred DMC rains descit.	V _{CC} = 5 V			130		nT/√ Hz	
B _{ND}	Input-referred RMS noise density	V _{CC} = 3.3 V			215		III/VHZ	
D	least as fermed as its	D 00 /00 //-	V _{CC} = 5 V		0.12		Т	
B _N	Input-referred noise	$B_{ND} \times 6.6 \times \sqrt{20 \text{ kHz}}$	$V_{CC} = 3.3 \text{ V}$		0.2		mT_PP	
	Output-referred noise (2)			DRV5055A1, DRV5055A5		12		
V _N		B _N × S	DRV5055A2		6		mV_PP	
			DRV5055A3		3		-	
			DRV5055A4		1.5			

⁽¹⁾ B is the applied magnetic flux density.

⁽²⁾ V_N describes voltage noise on the device output. If the full device bandwidth is not needed, noise can be reduced with an RC filter.



6.6 Magnetic Characteristics

for V_{CC} = 3 V to 3.63 V and 4.5 V to 5.5 V, over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDI	TIONS ⁽¹⁾	MIN	TYP	MAX	UNIT
.,			V _{CC} = 5 V	2.43	2.5	2.57	.,
V_Q	Quiescent voltage	$B = 0 \text{ mT}, T_A = 25^{\circ}\text{C}$	V _{CC} = 3.3 V	1.59	1.65	1.71	V
$V_{Q\Delta T}$	Quiescent voltage temperature drift	B = 0 mT, $T_A = -40$ °C to 150°C versus 25°C		±	1% × V _{CC}		V
V_{QRE}	Quiescent voltage ratiometry error ⁽²⁾				±0.2%		
$V_{Q\Delta L}$	Quiescent voltage lifetime drift	High-temperature ope 1000 hours	rating stress for		< 0.5%		
			DRV5055A1	95	100	105	
		.,	DRV5055A2	47.5	50	52.5	
		$V_{CC} = 5 \text{ V},$ $T_A = 25^{\circ}\text{C}$	DRV5055A3	23.8	25	26.2	
		1A - 23 O	DRV5055A4	11.9	12.5	13.2	
c	Sensitivity		DRV5055A5	-105	-100	-95	m\//mT
S		V _{CC} = 3.3 V, T _A = 25°C	DRV5055A1	57	60	63	mV/mT
			DRV5055A2	28.5	30	31.5	
			DRV5055A3	14.3	15	15.8	
			DRV5055A4	7.1	7.5	7.9	
			DRV5055A5	-63	-60	<i>–</i> 57	
		V _{CC} = 5 V, T _A = 25°C	DRV5055A1, DRV5055A5	±21			mT
			DRV5055A2	±42			
			DRV5055A3	±85			
_			DRV5055A4	±169			
B_L	Linear magnetic sensing range (3) (4)		DRV5055A1, DRV5055A5	±22			
		$V_{CC} = 3.3 \text{ V},$	DRV5055A2	±44			
		T _A = 25°C	DRV5055A3	±88			
			DRV5055A4	±176			
V _L	Linear range of output voltage ⁽⁴⁾			0.2		V _{CC} - 0.2	V
S _{TC}	Sensitivity temperature compensation for magnets (5)				0.12		%/°C
S _{LE}	Sensitivity linearity error ⁽⁴⁾	V _{OUT} is within V _L			±1%		
S _{SE}	Sensitivity symmetry error ⁽⁴⁾	V _{OUT} is within V _L			±1%		
S _{RE}	Sensitivity ratiometry error ⁽²⁾	$T_A = 25$ °C, with respect to $V_{CC} =$	3.3 V or 5 V	-2.5%		2.5%	
S _{ΔL}	Sensitivity lifetime drift	High-temperature ope 1000 hours	rating stress for		<0.5%		

⁽¹⁾ B is the applied magnetic flux density.

 ⁽²⁾ See the Ratiometric Architecture section.
 (3) B_L describes the minimum linear sensing range at 25°C taking into account the maximum V_Q and Sensitivity tolerances.

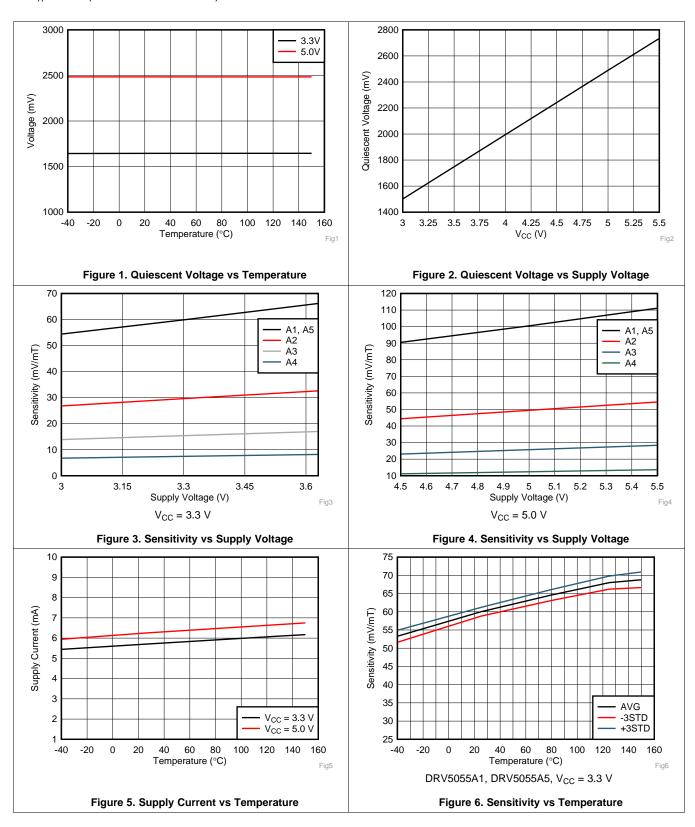
See the Sensitivity Linearity section.

S_{TC} describes the rate the device increases Sensitivity with temperature. For more information, see the Sensitivity Temperature Compensation for Magnets section.



6.7 Typical Characteristics

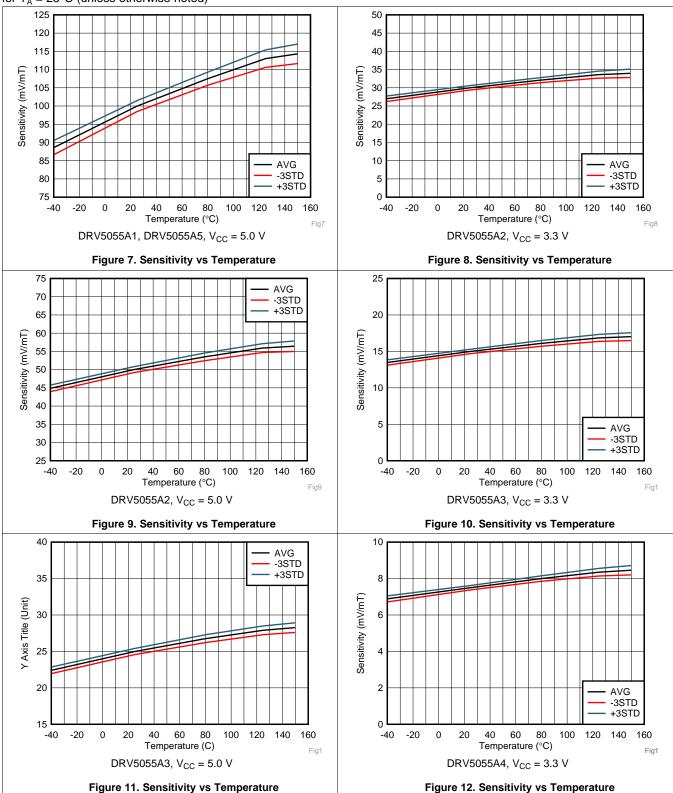
for $T_A = 25$ °C (unless otherwise noted)





Typical Characteristics (continued)

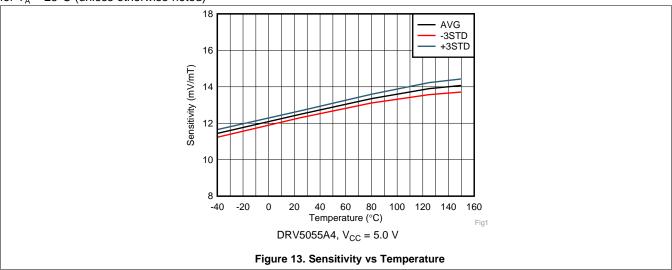
for $T_A = 25$ °C (unless otherwise noted)





Typical Characteristics (continued)

for $T_A = 25$ °C (unless otherwise noted)



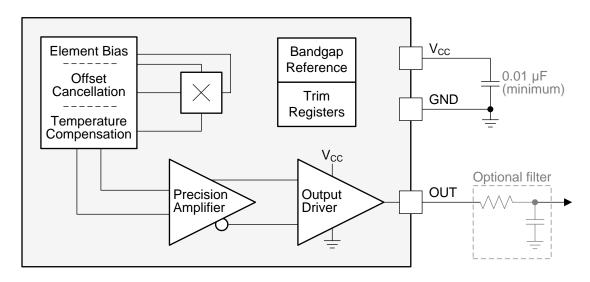


7 Detailed Description

7.1 Overview

The DRV5055-Q1 is a 3-pin linear Hall effect sensor with fully integrated signal conditioning, temperature compensation circuits, mechanical stress cancellation, and amplifiers. The device operates from 3.3-V and 5-V ($\pm 10\%$) power supplies, measures magnetic flux density, and outputs a proportional analog voltage that is referenced to V_{CC} .

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Magnetic Flux Direction

As shown in Figure 14, the DRV5055-Q1 is sensitive to the magnetic field component that is perpendicular to the top of the package.

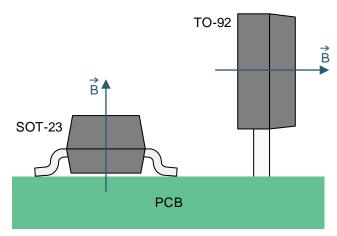


Figure 14. Direction of Sensitivity

Copyright © 2017–2018, Texas Instruments Incorporated



Magnetic flux that travels from the bottom to the top of the package is considered positive in this document. This condition exists when a south magnetic pole is near the top (marked-side) of the package. Magnetic flux that travels from the top to the bottom of the package results in negative millitesla values.

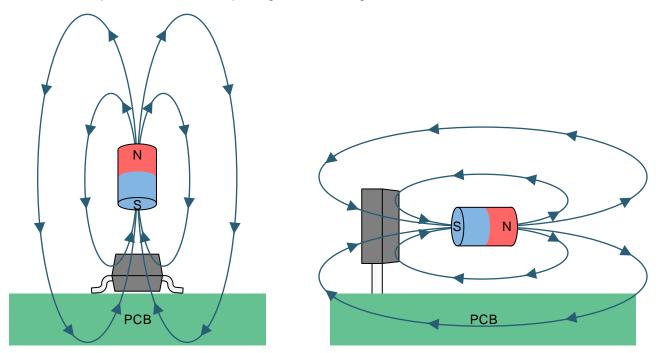


Figure 15. The Flux Direction for Positive B

7.3.2 Magnetic Response

When the DRV5055-Q1 is powered, the DRV5055-Q1 outputs an analog voltage according to Equation 1:

$$V_{OUT} = V_Q + B \times (Sensitivity_{(25^{\circ}C)} \times (1 + S_{TC} \times (T_A - 25^{\circ}C)))$$

where

- V_Q is typically half of V_{CC}
- · B is the applied magnetic flux density
- Sensitivity_(25°C) depends on the device option and V_{CC}
- S_{TC} is typically 0.12%/°C
- T_A is the ambient temperature
- V_{OUT} is within the V_L range

(1)

As an example, consider the DRV5055A3 with $V_{CC}=3.3$ V, a temperature of 50°C, and 67 mT applied. Excluding tolerances, $V_{OUT}=1650$ mV + 67 mT × (15 mV/mT × (1 + 0.0012/°C × (50°C - 25°C))) = 2685 mV.

7.3.3 Sensitivity Linearity

The device produces a linear response when the output voltage is within the specified V_L range. Outside this range, sensitivity is reduced and nonlinear. Figure 16 and Figure 17 graph the magnetic response.



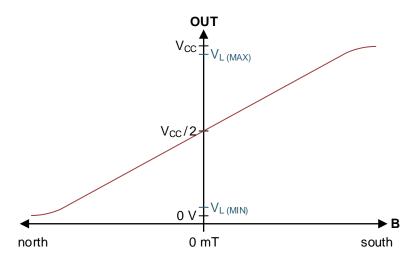


Figure 16. Magnetic Response of the A1, A2, A3, A4 Versions

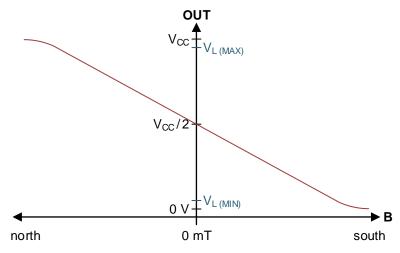


Figure 17. Magnetic Response of the A5 Version

Equation 2 calculates parameter B_I, the minimum linear sensing range at 25°C taking into account the maximum

quiescent voltage and sensitivity tolerances.
$$B_{L(MIN)} = \frac{V_{L(MAX)} - V_{Q(MAX)}}{S_{(MAX)}}$$
 (2)

The parameter S_{LE} defines linearity error as the difference in sensitivity between any two positive B values, and any two negative B values, while the output is within the V_L range.

The parameter S_{SF} defines symmetry error as the difference in sensitivity between any positive B value and the negative B value of the same magnitude, while the output voltage is within the V_L range.

7.3.4 Ratiometric Architecture

The DRV5055-Q1 has a ratiometric analog architecture that scales the quiescent voltage and sensitivity linearly with the power-supply voltage. For example, the quiescent voltage and sensitivity are 5% higher when V_{CC} = 5.25 V compared to \dot{V}_{CC} = 5 V. This behavior enables external ADCs to digitize a consistent value regardless of the power-supply voltage tolerance, when the ADC uses V_{CC} as its reference.

Copyright © 2017-2018, Texas Instruments Incorporated



Equation 3 calculates the sensitivity ratiometry error:

$$S_{RE} = 1 - \frac{S_{(VCC)} / S_{(5V)}}{V_{CC} / 5V} \ \, \text{for} \ \, V_{CC} = 4.5 \ \, V \ \, \text{to} \ \, 5.5 \ \, V, \\ S_{RE} = 1 - \frac{S_{(VCC)} / S_{(3.3V)}}{V_{CC} / 3.3V} \ \, \text{for} \ \, V_{CC} = 3 \ \, V \ \, \text{to} \ \, 3.63 \ \, V, \\ S_{RE} = 1 - \frac{S_{(VCC)} / S_{(3.3V)}}{V_{CC} / 3.3V} \ \, \text{for} \ \, V_{CC} = 3 \ \, V \ \, \text{to} \ \, 3.63 \ \, V, \\ S_{RE} = 1 - \frac{S_{(VCC)} / S_{(3.3V)}}{V_{CC} / 3.3V} \ \, \text{for} \ \, V_{CC} = 3 \ \, V \ \, \text{to} \ \, 3.63 \ \, V \ \, \text{to} \ \, \text{t$$

where

- S_(VCC) is the sensitivity at the current V_{CC} voltage
- $S_{(5V)}$ or $S_{(3.3V)}$ is the sensitivity when $V_{CC} = 5 \text{ V}$ or 3.3 V

•
$$V_{CC}$$
 is the current V_{CC} voltage (3)

Equation 4 calculates quiescent voltage ratiometry error:

$$V_{QRE} = 1 - \frac{V_{Q(VCC)} / V_{Q(5V)}}{V_{CC} / 5V} \text{ for } V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}, \qquad V_{QRE} = 1 - \frac{V_{Q(VCC)} / V_{Q(3.3V)}}{V_{CC} / 3.3V} \text{ for } V_{CC} = 3 \text{ V to } 3.63 \text{ V}$$

where

- V_{Q(VCC)} is the quiescent voltage at the current V_{CC} voltage
- $V_{Q(5V)}$ or $V_{Q(3.3V)}$ is the quiescent voltage when $V_{CC} = 5 \text{ V}$ or 3.3 V

•
$$V_{CC}$$
 is the current V_{CC} voltage (4)

7.3.5 Operating V_{CC} Ranges

The DRV5055-Q1 has two recommended operating V_{CC} ranges: 3 V to 3.63 V and 4.5 V to 5.5 V. When V_{CC} is in the middle region between 3.63 V to 4.5 V, the device continues to function, but sensitivity is less known because there is a crossover threshold near 4 V that adjusts device characteristics.

7.3.6 Sensitivity Temperature Compensation for Magnets

Magnets generally produce weaker fields as temperature increases. The DRV5055-Q1 compensates by increasing sensitivity with temperature, as defined by the parameter S_{TC} . The sensitivity at T_A = 125°C is typically 12% higher than at T_A = 25°C. The DRV5055A5 absolute value of sensitivity increases with temperature.

7.3.7 Power-On Time

After the V_{CC} voltage is applied, the DRV5055-Q1 requires a short initialization time before the output is set. The parameter t_{ON} describes the time from when V_{CC} crosses 3 V until OUT is within 5% of V_{Q} , with 0 mT applied and no load attached to OUT. Figure 18 shows this timing diagram.

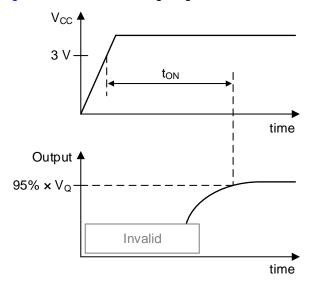


Figure 18. t_{ON} Definition

Submit Documentation Feedback

Copyright © 2017–2018, Texas Instruments Incorporated



7.3.8 Hall Element Location

Figure 19 shows the location of the sensing element inside each package option.

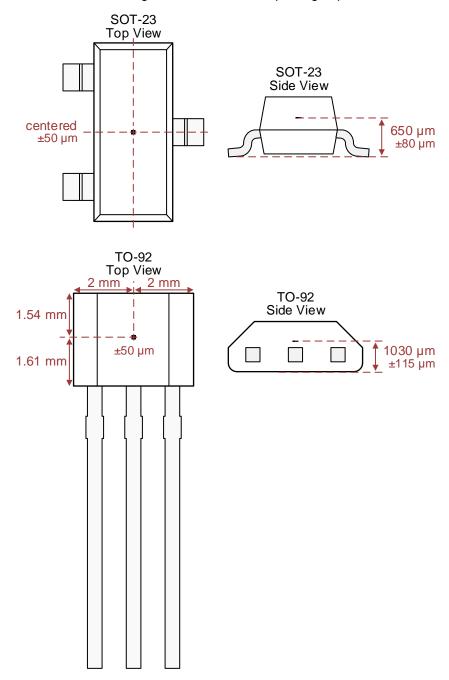


Figure 19. Hall Element Location

7.4 Device Functional Modes

The DRV5055-Q1 has one mode of operation that applies when the *Recommended Operating Conditions* are met.

Copyright © 2017–2018, Texas Instruments Incorporated



8 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

8.1.1 Selecting the Sensitivity Option

Select the highest DRV5055-Q1 sensitivity option that can measure the required range of magnetic flux density, so that the output voltage swing is maximized.

Larger-sized magnets and farther sensing distances can generally enable better positional accuracy than very small magnets at close distances, because magnetic flux density increases exponentially with the proximity to a magnet. TI created an online tool to help with simple magnet calculations at http://www.ti.com/product/drv5013.

8.1.2 Temperature Compensation for Magnets

The DRV5055-Q1 temperature compensation is designed to directly compensate the average drift of neodymium (NdFeB) magnets and partially compensate ferrite magnets. The residual induction (B_r) of a magnet typically reduces by 0.12%/°C for NdFeB, and 0.20%/°C for ferrite. When the operating temperature of a system is reduced, temperature drift errors are also reduced.

8.1.3 Adding a Low-Pass Filter

As shown in the *Functional Block Diagram*, an RC low-pass filter can be added to the device output for the purpose of minimizing voltage noise when the full 20-kHz bandwidth is not needed. This filter can improve the signal-to-noise ratio (SNR) and overall accuracy. Do not connect a capacitor directly to the device output without a resistor in between because doing so can make the output unstable.

8.1.4 Designing for Wire Break Detection

Some systems must detect if interconnect wires become open or shorted. The DRV5055-Q1 can support this function.

First, select a sensitivity option that causes the output voltage to stay within the V_L range during normal operation. Second, add a pullup resistor between OUT and V_{CC} . TI recommends a value between 20 k Ω to 100 k Ω , and the current through OUT must not exceed the I_O specification, including current going into an external ADC. Then, if the output voltage is ever measured to be within 150 mV of V_{CC} or GND, a fault condition exists. Figure 20 shows the circuit, and Table 1 describes fault scenarios.

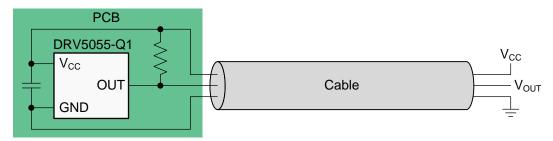


Figure 20. Wire Fault Detection Circuit



Table 1. Fault Scenarios and the Resulting Vout

FAULT SCENARIO	V _{OUT}	
V _{CC} disconnects	Close to GND	
GND disconnects	Close to V _{CC}	
V _{CC} shorts to OUT	Close to V _{CC}	
GND shorts to OUT	Close to GND	

8.2 Typical Application

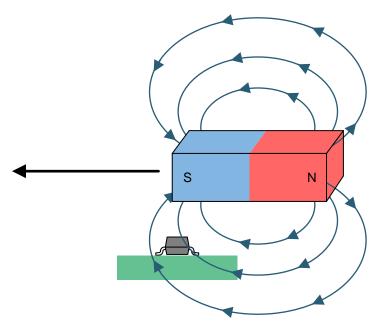


Figure 21. Common Magnet Orientation

8.2.1 Design Requirements

Use the parameters listed in Table 2 for this design example.

Table 2. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
V _{CC}	5 V
Magnet	15 x 5 x 5 mm NdFeB
Travel distance	12 mm
Maximum B at the sensor at 25°C	±75 mT
Device option	DRV5055A3

8.2.2 Detailed Design Procedure

Linear Hall effect sensors provide flexibility in mechanical design, because many possible magnet orientations and movements produce a usable response from the sensor. Figure 21 shows one of the most common orientations, which uses the full north to south range of the sensor and causes a close-to-linear change in magnetic flux density as the magnet moves across.

When designing a linear magnetic sensing system, always consider these three variables: the magnet, sensing distance, and the range of the sensor. Select the DRV5055-Q1 with the highest sensitivity that has a B_L (linear magnetic sensing range) that is larger than the maximum magnetic flux density in the application. To determine the magnetic flux density the sensor receives, TI recommends using magnetic field simulation software, referring to magnet specifications, and testing.

Copyright © 2017–2018, Texas Instruments Incorporated



8.2.3 Application Curve

Figure 22 shows the simulated magnetic flux from a NdFeB magnet.

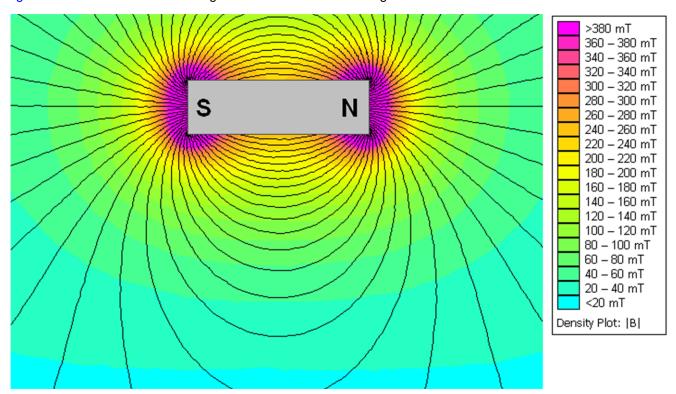


Figure 22. Simulated Magnetic Flux



8.3 Do's and Don'ts

Because the Hall element is sensitive to magnetic fields that are perpendicular to the top of the package, a correct magnet approach must be used for the sensor to detect the field. Figure 23 shows correct and incorrect approaches.

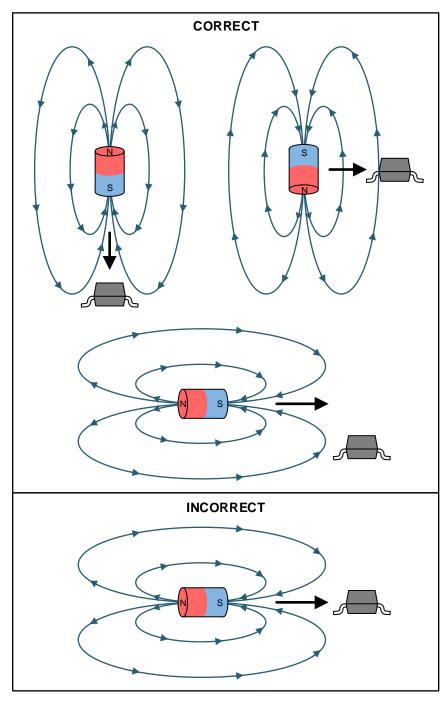


Figure 23. Correct and Incorrect Magnet Approaches



9 Power Supply Recommendations

A decoupling capacitor close to the device must be used to provide local energy with minimal inductance. TI recommends using a ceramic capacitor with a value of at least 0.01 µF.

10 Layout

10.1 Layout Guidelines

Magnetic fields pass through most nonferromagnetic materials with no significant disturbance. Embedding Hall effect sensors within plastic or aluminum enclosures and sensing magnets on the outside is common practice. Magnetic fields also easily pass through most printed-circuit boards, which makes placing the magnet on the opposite side possible.

10.2 Layout Examples

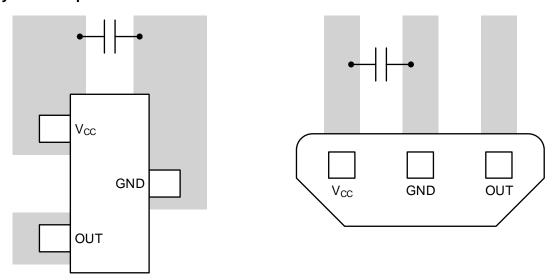


Figure 24. Layout Examples



11 Device and Documentation Support

11.1 Documentation Support

11.1.1 Related Documentation

For related documentation see the following:

- Using Linear Hall Effect Sensors to Measure Angle
- Incremental Rotary Encoder Design Considerations

11.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.4 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

11.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.





10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
DRV5055A1EDBZRQ1	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	SN	Level-3-260C-168 HR	-40 to 150	55A1Z	Samples
DRV5055A1ELPGMQ1	ACTIVE	TO-92	LPG	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A1Z	Samples
DRV5055A1ELPGQ1	ACTIVE	TO-92	LPG	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A1Z	Samples
DRV5055A2EDBZRQ1	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	SN	Level-3-260C-168 HR	-40 to 150	55A2Z	Samples
DRV5055A2ELPGMQ1	ACTIVE	TO-92	LPG	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A2Z	Samples
DRV5055A2ELPGQ1	ACTIVE	TO-92	LPG	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A2Z	Samples
DRV5055A3EDBZRQ1	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	SN	Level-3-260C-168 HR	-40 to 150	55A3Z	Samples
DRV5055A3ELPGMQ1	ACTIVE	TO-92	LPG	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A3Z	Samples
DRV5055A3ELPGQ1	ACTIVE	TO-92	LPG	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A3Z	Samples
DRV5055A4EDBZRQ1	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	SN	Level-3-260C-168 HR	-40 to 150	55A4Z	Samples
DRV5055A4ELPGMQ1	ACTIVE	TO-92	LPG	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A4Z	Samples
DRV5055A4ELPGQ1	ACTIVE	TO-92	LPG	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	55A4Z	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.



PACKAGE OPTION ADDENDUM

10-Dec-2020

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF DRV5055-Q1:

Catalog: DRV5055

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

www.ti.com 19-Jan-2019

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

All difficults are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DRV5055A1EDBZRQ1	SOT-23	DBZ	3	3000	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3
DRV5055A2EDBZRQ1	SOT-23	DBZ	3	3000	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3
DRV5055A3EDBZRQ1	SOT-23	DBZ	3	3000	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3
DRV5055A4EDBZRQ1	SOT-23	DBZ	3	3000	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3

www.ti.com 19-Jan-2019



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DRV5055A1EDBZRQ1	SOT-23	DBZ	3	3000	213.0	191.0	35.0
DRV5055A2EDBZRQ1	SOT-23	DBZ	3	3000	213.0	191.0	35.0
DRV5055A3EDBZRQ1	SOT-23	DBZ	3	3000	213.0	191.0	35.0
DRV5055A4EDBZRQ1	SOT-23	DBZ	3	3000	213.0	191.0	35.0



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4203227/C





SMALL OUTLINE TRANSISTOR



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.
 Reference JEDEC registration TO-236, except minimum foot length.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 4. Publication IPC-7351 may have alternate designs.5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



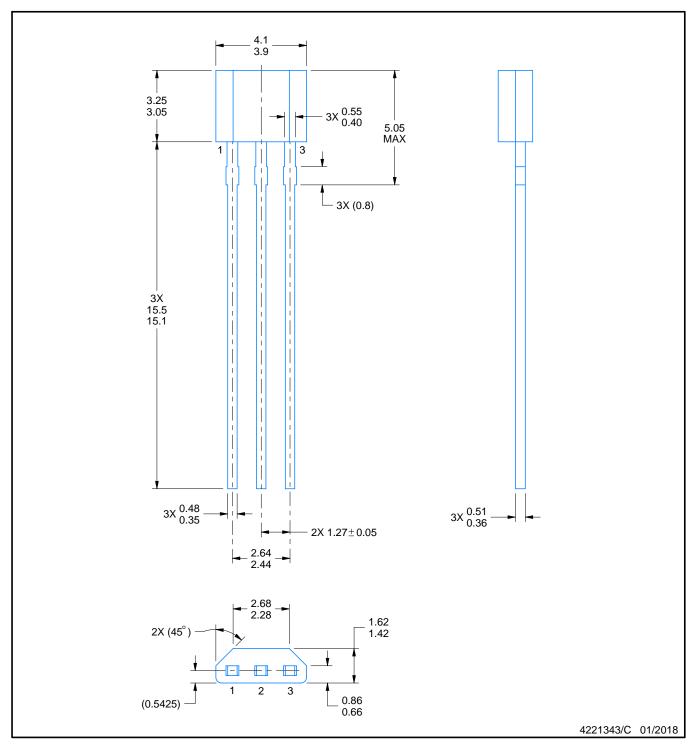
NOTES: (continued)

- 6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 7. Board assembly site may have different recommendations for stencil design.





TRANSISTOR OUTLINE



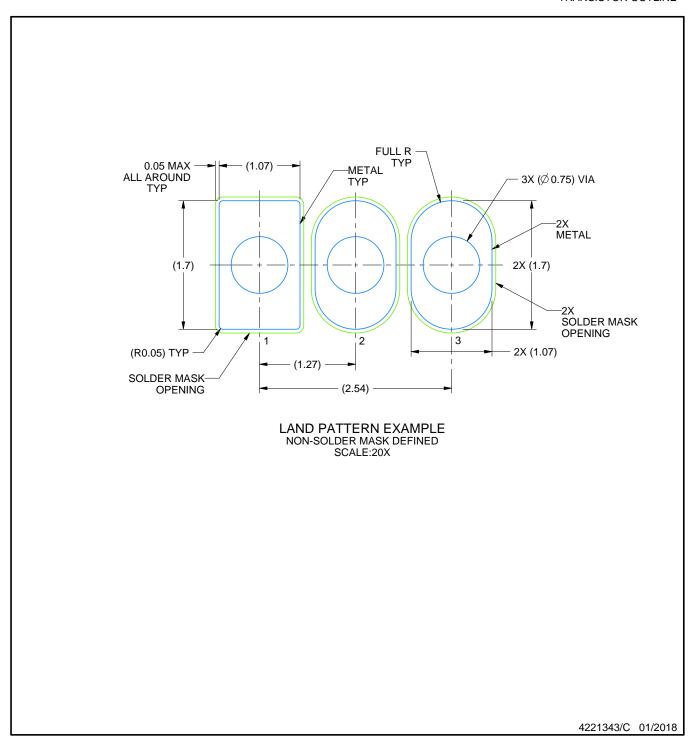
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

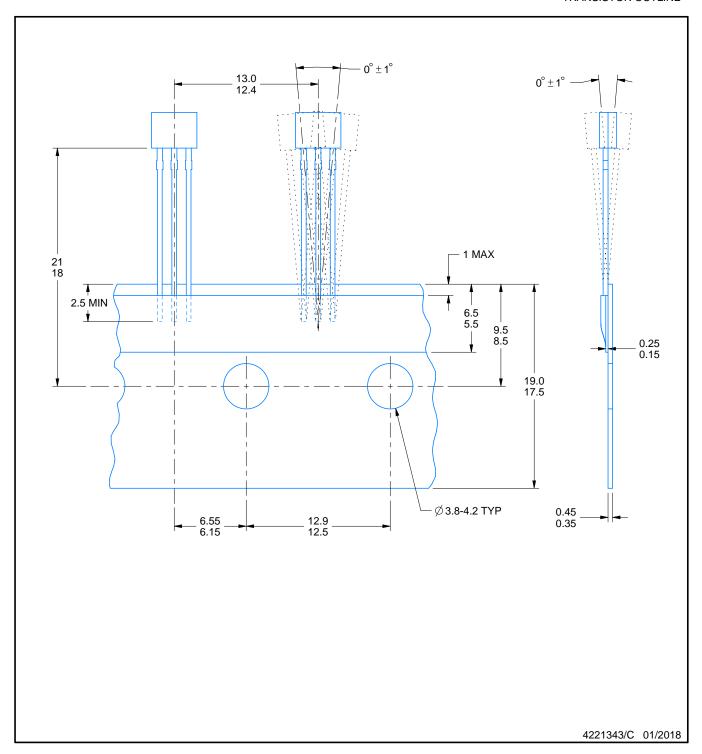
 2. This drawing is subject to change without notice.



TRANSISTOR OUTLINE



TRANSISTOR OUTLINE



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

Tl's products are provided subject to Tl's Terms of Sale (www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such Tl products. Tl's provision of these resources does not expand or otherwise alter Tl's applicable warranties or warranty disclaimers for Tl products.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2020, Texas Instruments Incorporated